

**Search Notes****Application/Control No.**

10/572,961

**Examiner**

CHRIS C. CHU

**Applicant(s)/Patent under Reexamination**

FUKUDA ET AL.

**Art Unit**

2815

**SEARCHED**

Class	Subclass	Date	Examiner
257	E23,188, E23,009, 712 & 703	11/4/2008	C.C.
257	706 & 750	11/4/2008	C.C.
257	700	11/4/2008	C.C.
428	469 & 698	11/4/2008	C.C.
428	209 & 210	11/4/2008	C.C.
361	704	11/4/2008	C.C.
228	121	11/4/2008	C.C.

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Searched in US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; and IBM_TDB;	11/4/2008	C.C.

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
As same	as above	11/4/2008	C.C.